NTDS PCIe Type E (LLS) Interface Adapter

Specifications

GET Part Number
10078001 (Standard)
10078001-L (Low Profile)

NTDS Serial Interface
MIL-STD-1397C Type E

Form Factor
Low Profile PCIe
(167.65 mm X 68.9 mm)

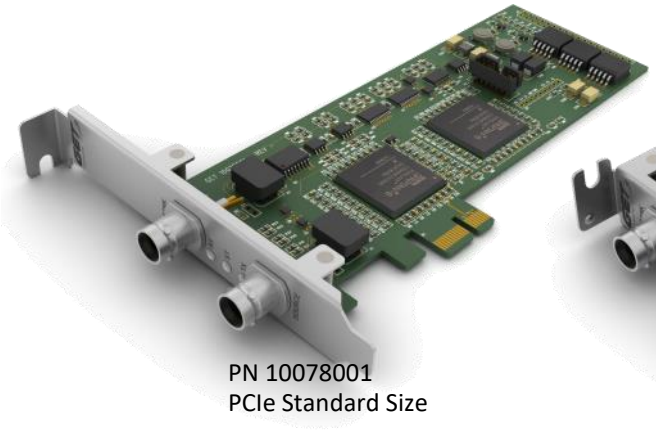
Bus Interface
PCI Express x1 Gen 1

Power Requirements
+5 VDC @ 1.4 Amp (typ)
-12 VDC @ .2Amp (typ)

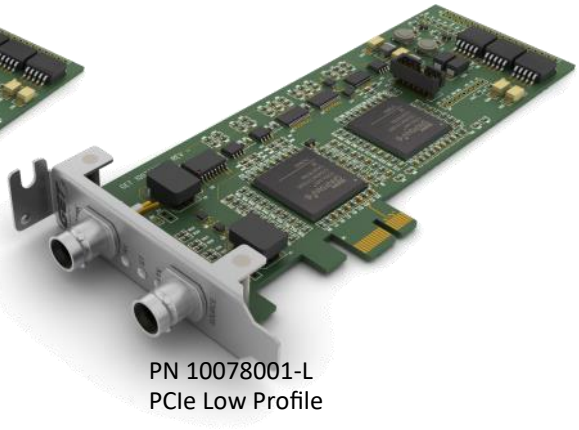
NTDS I/O connectors
BJ77 TRIAX

Extended Temperature
-40°C to 85°C Operating
(ANSI/VITA 47, Class CC4)

Ordering Options
Standard - 10078001
Low-Profile - 10078001-L



PN 10078001
PCIe Standard Size



PN 10078001-L
PCIe Low Profile

GET Engineering, the Industry Leader in MIL-STD-1397C Products, introduces its **NTDS PCIe Type E (LLS) Interface Adapter**. Innovative design and cutting edge Field Programmable Gate Array (FPGA) technology combine to deliver superior performance and exceptional reliability while providing fully compliant MIL-STD-1397C communications. FPGA controlled DMA channels for transmit and receive buffers reduce host CPU overhead. The low profile design gives the system builder the flexibility of installing the unit in a 2U rack mount or small form factor (SFF) desktop enclosure.

Software Driver Support includes a full featured Common User Interface (CUI) driver. The CUI driver API calls are operating system independent and thereby provide an easy migration path when porting code between operating systems.

GET Engineering's NTDS PCIe Type E (LLS) Interface Adapter is extended temperature rated and is shipped with either a standard or low profile rear panel bracket.

9350 Bond Avenue • El Cajon, CA 92021 • Tel: 619.443.8295 • Fax: 619.443.8613 • www.getntds.com

NTDS PCIe Type E (LLS) Interface Adapter

Environmental Specifications

Operating Temperature Range
Minus 40° to 85°C Operating (ANSI-VITA 47, Class CC4)

Storage Temperature
Minus 40° to 85°C Operating (MIL-STD-810 Method 501 and 502, Procedure I)

Vibration
0.01g²/Hz 15-2 KHz, Optional 0.1g²/HZ 15-2KHz, (MIL-STD-810, Method 514, Procedure I)

Operating Shock
20 g peak, Optional 40 g Peak, (MILSTD-810, Method 516, Procedure I)

Humidity
5% to 95% humidity operational (non-condensing) (MIL-STD-810, Method 507)

Mean Time Between Failures (MTBF)
> 200K Hours per MIL-HDBK-217, Rev E, 25°C Ground Benign Environment

Key Features

- NTDS Type E Low Level Serial
- 100% MIL-STD-1397C Compliant
- Full-duplex 16 or 32-bit transfers
- Rear panel (BJ77 TRIAX) accessible I/O connectors
- Reconfigurable to support specific applications
- Independent Input and Output ports
- PIO Single Word Transfers
- Operate at maximum NTDS transfer rates
- True Full Duplex operation
- Buffer / Command Time-outs: 1 µs granularity
- Inter-word Timers: 1 µs granularity
- Platform & operating system independent software
- Field Upgradeable Firmware and Software Drivers
- Internal Loop-Back: test adapter operation without external cables
- Multiple Built In Self Test (BIST) support options

Transmit Features

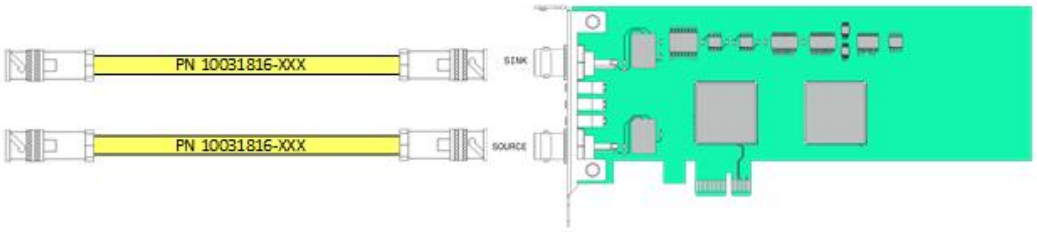
- Transceiver Short Circuit and Transient Protection
- Information Frame Parity and Control Frame ID control
- Extensive SIF support to improve system reliability
- Single word, Burst, and Forced Function Modes

Receive Features

- Single word, Burst, and Forced Function Modes

Connection Options

- Other options available.



PCIe Serial

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